

Elements of electrical and optical connection — Test methods —

Part 306: Mould growth

The European Standard EN 2591-306:1998 has the status of a
British Standard

ICS 49.060

National foreword

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Summary of pages

This document comprises a front cover, an inside front cover, pages i and ii, the EN title page, pages 2 to 6 and a back cover.

This standard has been updated (see copyright date) and may have had amendments incorporated. This will be indicated in the amendment table on the inside front cover.

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